

**Search Notes**

Application/Control No.

10/773,179

Examiner

Emmanuel Bayard

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	260	3/19/2007	EB
375	261	3/19/2007	EB
375	285	3/19/2007	EB
375	295	3/19/2007	EB
375	296	3/19/2007	EB
370	208	3/19/2007	EB
370	209	3/19/2007	EB
370	210	3/19/2007	EB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	3/19/2007	EB